

Notice of References Cited	Application/Control No. 10/617,911	Applicant(s)/Patent Under Reexamination YIP ET AL.	
	Examiner Soon D. Hyun	Art Unit 2616	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,243,342	09-1993	Kattemalalavadi et al.	341/106
*	B	US-5,309,430	05-1994	Verhille et al.	370/397
*	C	US-5,353,283	10-1994	Tsuchiya, Paul F.	370/392
*	D	US-7,154,889	12-2006	Rekhter et al.	370/392
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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